Search Notes		

1	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/661,746	HSIEH, CHIA-TA
П	Examiner	Art Unit
	Eric B. Chen	1765

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Performed inventor search for double patenting (PALM, eDAN)	7/18/2005	EC	
EAST (all databases) - see search history printout	7/19/2005	EC	
257/314-316; 438/266,585-587,706, 710,719,723,724,735,745,756,770 (text search only - see search history) (consulted K. Chen)	7/19/2005	EC	
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